

IR2011(S) & (PbF)

HIGH AND LOW SIDE DRIVER

Features

- Floating channel designed for bootstrap operation Fully operational up to +200V Tolerant to negative transient voltage, dV/dt immune
- Gate drive supply range from 10V to 20V
- Independent low and high side channels
- Input logic HIN/LIN active high
- Undervoltage lockout for both channels
- 3.3V and 5V input logic compatible
- CMOS Schmitt-triggered inputs with pull-down
- Matched propagation delay for both channels
- 8-Lead SOIC is also available LEAD-FREE (PbF)

Applications

- Audio Class D amplifiers
- High power DC-DC SMPS converters
- Other high frequency applications

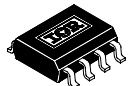
Description

The IR2011 is a high power, high speed power MOSFET driver with independent high and low side referenced output channels, ideal for Audio Class D and DC-DC converter applications. Logic inputs are compatible with standard CMOS or LSTTL output, down to 3.0V logic. The output drivers feature a high pulse current buffer stage designed for minimum driver cross-conduction. Propagation delays are matched to simplify use in high frequency applications. The floating channel can be used to drive an N-channel power MOSFET in the high side configuration which operates up to 200 volts. Proprietary HVIC and latch immune CMOS technologies enable ruggedized monolithic construction.

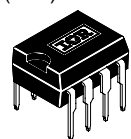
Product Summary

V_{OFFSET}	200V max.
$I_{O+/-}$	1.0A /1.0A typ.
V_{OUT}	10 - 20V
$t_{on/off}$	80 & 60 ns typ.
Delay Matching	20 ns max.

Packages

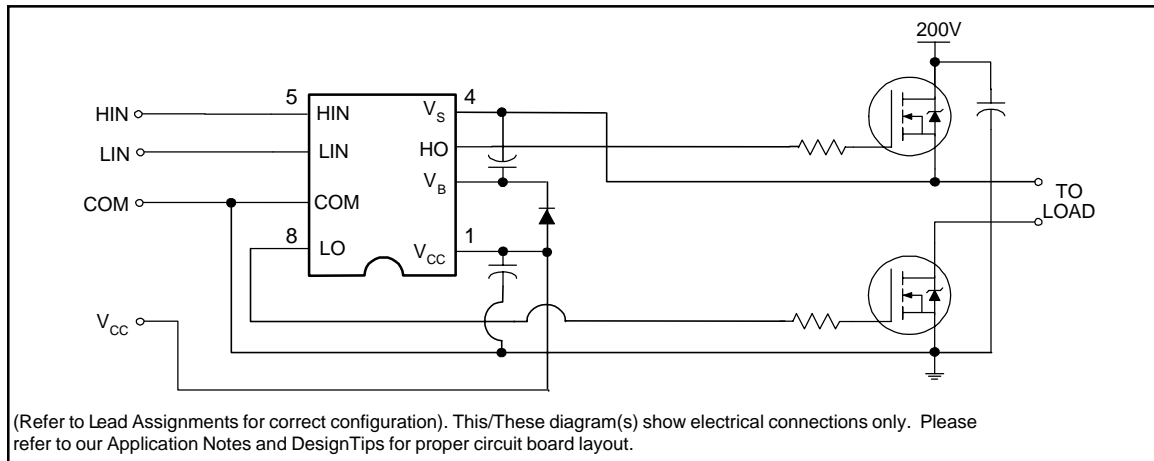


8-Lead SOIC
 IR2011S
 also available
 LEAD-FREE (PbF)



8-Lead PDIP
 IR2011

Typical Connection



IR2011(S) & (PbF)

Absolute Maximum Ratings

Absolute maximum ratings indicate sustained limits beyond which damage to the device may occur. All voltage parameters are absolute voltages referenced to COM. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions.

Symbol	Definition	Min.	Max.	Units	
V _B	High side floating supply voltage	-0.3	250	V	
V _S	High side floating supply offset voltage	V _B - 25	V _B + 0.3		
V _{HO}	High side floating output voltage	V _S - 0.3	V _B + 0.3		
V _{CC}	Low side fixed supply voltage	-0.3	25		
V _{LO}	Low side output voltage	-0.3	V _{CC} + 0.3		
V _{IN}	Logic input voltage (HIN & LIN)	COM - 0.3	V _{CC} + 0.3		
dV _S /dt	Allowable offset supply voltage transient (figure 2)	—	50	V/ns	
P _D	Package power dissipation @ T _A ≤ +25°C	(8-lead DIP)	—	1.0	W
		(8-lead SOIC)	—	0.625	
R _{THJA}	Thermal resistance, junction to ambient	(8-lead DIP)	—	125	°C/W
		(8-lead SOIC)	—	200	
T _J	Junction temperature	—	150	°C	
T _S	Storage temperature	-55	150		
T _L	Lead temperature (soldering, 10 seconds)	—	300		

Recommended Operating Conditions

For proper operation the device should be used within the recommended conditions. The V_S and COM offset ratings are tested with all supplies biased at 15V differential.

Symbol	Definition	Min.	Max.	Units
V _B	High side floating supply absolute voltage	V _S + 10	V _S + 20	V
V _S	High side floating supply offset voltage	Note 1	200	
V _{HO}	High side floating output voltage	V _S	V _B	
V _{CC}	Low side fixed supply voltage	10	20	
V _{LO}	Low side output voltage	0	V _{CC}	
V _{IN}	Logic input voltage (HIN & LIN)	COM	5.5	
T _A	Ambient temperature	-40	125	

Note 1: Logic operational for V_S of -4 to +200V. Logic state held for V_S of -4V to -V_{BS}.

Dynamic Electrical Characteristics

$V_{BIAS} (V_{CC}, V_{BS}) = 15V$, $C_L = 1000 \text{ pF}$, $T_A = 25^\circ\text{C}$ unless otherwise specified. Figure 1 shows the timing definitions.

Symbol	Definition	Min.	Typ.	Max.	Units	Test Conditions
t_{on}	Turn-on propagation delay	—	80	—	ns	$V_S = 0V$
t_{off}	Turn-off propagation delay	—	75	—		$V_S = 200V$
t_r	Turn-on rise time	—	35	50		
t_f	Turn-off fall time	—	20	35		
DM1	Turn-on delay matching $t_{on} (H) - t_{on} (L) $	—	5	20		
DM2	Turn-off delay matching $t_{off} (H) - t_{off} (L) $	—	5	20		

Static Electrical Characteristics

$V_{BIAS} (V_{CC}, V_{BS}) = 15V$, and $T_A = 25^\circ\text{C}$ unless otherwise specified. The V_{IN} , V_{TH} and I_{IN} parameters are referenced to COM and are applicable to all logic input leads: HIN and LIN. The V_O and I_O parameters are referenced to COM and are applicable to the respective output leads: HO or LO.

Symbol	Definition	Min.	Typ.	Max.	Units	Test Conditions
V_{IH}	Logic "1" input voltage	2.2	—	—	V	$V_{CC} = 10V - 20V$
V_{IL}	Logic "0" input voltage	—	—	0.7		
V_{OH}	High level output voltage, $V_{BIAS} - V_O$	—	—	2.0		$I_O = 0A$
V_{OL}	Low level output voltage, V_O	—	—	0.2		20mA
I_{LK}	Offset supply leakage current	—	—	50	μA	$V_B = V_S = 200V$
I_{QBS}	Quiescent V_{BS} supply current	—	90	210		$V_{IN} = 0V$ or $3.3V$
I_{QCC}	Quiescent V_{CC} supply current	—	140	230		$V_{IN} = 0V$ or $3.3V$
I_{IN+}	Logic "1" input bias current	—	7.0	20		$V_{IN} = 3.3V$
I_{IN-}	Logic "0" input bias current	—	—	1.0		$V_{IN} = 0V$
V_{BSUV+}	V_{BS} supply undervoltage positive going threshold	8.2	9.0	9.8	V	
V_{BSUV-}	V_{BS} supply undervoltage negative going threshold	7.4	8.2	9.0		
V_{CCUV+}	V_{CC} supply undervoltage positive going threshold	8.2	9.0	9.8		
V_{CCUV-}	V_{CC} supply undervoltage negative going threshold	7.4	8.2	9.0		
I_{O+}	Output high short circuit pulsed current	—	1.0	—	A	$V_O = 0V$, $PW \leq 10 \mu s$
I_{O-}	Output low short circuit pulsed current	—	1.0	—		$V_O = 15V$, $PW \leq 10 \mu s$